

Notice of References Cited	Application/Control No. 10/687,111	Applicant(s)/Patent Under Reexamination DOAN, TRUNG T.	
	Examiner Jack I. Berman	Art Unit 2881	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-3,868,507	02-1975	Panitz, John A.	250/306
	B	US-5,475,318	12-1995	Marcus et al.	250/306
	C	US-5,633,455	05-1997	Quate, Calvin F.	250/307
	D	US-6,576,900	06-2003	Kelly et al.	250/307
	E	US-2004/0056195	03-2004	Kuhlman et al.	250/307
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Marcus et al., "Formation of silicon tips with < 1 nm radius", Applied Physics Letters 56 (3), 15 January 1990, pp. 236-238.
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.